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Application/Control No.	Applicant(s)/Patent under Reexamination
10/563,220	KAMIYA ET AL.
Examiner	Art Unit
Sean P. Shechtman	2125

	SEARCHED			
Class	Subclass	Date	Examiner	
700	83,87,108- 182			
715	964			
703	6	10/26/2007	SPS	
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INI	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East Search Attached	10/26/2007	SPS		